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Contents

vii *Conference Committee*

IMAGE AND SIGNAL PROCESSING I

7877 02 **Lipschitz exponents based signal restoration** [7877-01]
B. Jalil, O. Beya, E. Fauvet, O. Laligant, Le2i, CNRS, Univ. de Bourgogne (France)

7877 03 **Real-time wavelet-based inline banknote-in-bundle counting for cut-and-bundle machines** [7877-02]
D. Petker, OWITA GmbH (Germany); V. Lohweg, E. Gillich, Ostwestfalen-Lippe Univ. of Applied Sciences (Germany); T. Türke, KBA-NotaSys SARL (Switzerland); H. Willeke, J. Lochmüller, KBA-Bielefeld (Germany); J. Schaede, KBA-NotaSys SARL (Switzerland)

7877 04 **A robust segmentation and tracking method for characterizing GNSS signals reception environment** [7877-03]
A. Cohen, C. Meurie, Y. Ruichek, Univ. de Technologie de Belfort-Montbéliard (France); J. Marais, Univ. Lille Nord de France (France)

IMAGE AND SIGNAL PROCESSING II

7877 05 **Accurate, fast, and robust centre localisation for images of semiconductor components** [7877-04]
F. Timm, Univ. of Lübeck (Germany) and Pattern Recognition Co. GmbH (Germany); E. Barth, Univ. of Lübeck (Germany)

7877 06 **A 2D histogram representation of images for pooling** [7877-27]
X. Yu, Y.-J. Zhang, Tsinghua Univ. (China)

7877 07 **Gram polynomial image decimation and its application to non-rigid registration** [7877-06]
A. Badshah, P. O'Leary, M. Harker, Montan Univ. Leoben (Austria)

7877 08 **Interactive image quantification tools in nuclear material forensics** [7877-07]
R. Porter, C. Ruggiero, D. Hush, N. Harvey, P. Kelly, W. Scoggins, L. Tandon, Los Alamos National Lab. (United States)

OUTDOOR VISION

7877 09 **Line segment based structure and motion from two views** [7877-28]
S. Mosaddegh, A. Fazlollahi, D. Fofi, Le2i, CNRS, Univ. de Bourgogne (France); P. Vasseur, Univ. de Picardie Jules Verne (France)

7877 0A **Vision based forest smoke detection using analyzing of temporal patterns of smoke and their probability models** [7877-09]
S. Ham, B.-C. Ko, J.-Y. Nam, Keimyung Univ. (Korea, Republic of)

7877 0B **Estimation of fire volume by stereovision** [7877-10]
T. Molinier, L. Rossi, SPE, CNRS, Univ. of Corsica (France); M. Akhloufi, Ctr. of Robotics and Vision (Canada); Y. Tison, A. Pieri, SPE, CNRS, Univ. of Corsica (France)

7877 0C **Pavement distress detection and severity analysis** [7877-11]
E. Salari, G. Bao, The Univ. of Toledo (United States)

FEATURES AND PATTERN RECOGNITION

7877 0F **Multi-frame decision level fusion for face classification based on a photon-counting linear discriminant analysis** [7877-14]
S. Yeom, Daegu Univ. (Korea, Republic of)

7877 0G **Pose-robust face recognition using shape-adapted texture features** [7877-15]
T. Gernoth, A. Gooßen, R.-R. Grigat, Technische Univ. Hamburg-Harburg (Germany)

MEDICAL IMAGING

7877 0H **A novel framework for white blood cell segmentation based on stepwise rules and morphological features** [7877-16]
J.-W. Gim, J. Park, J.-H. Lee, B. Ko, J.-Y. Nam, Keimyung Univ. (Korea, Republic of)

7877 0I **Image fusion on redundant lifting non-separable wavelet transforms** [7877-17]
W. Wang, Chang'an Univ. (China); J. Zeng, Univ. of Electronic Science and Technology of China (China); S. Yin, X. Wang, Chang'an Univ. (China)

MACHINE VISION AND INDUSTRIAL APPLICATIONS I

7877 0J **Non-parametric texture defect detection using Weibull features** [7877-18]
F. Timm, Univ. of Lübeck (Germany) and Pattern Recognition Co. GmbH (Germany); E. Barth, Univ. of Lübeck (Germany)

7877 0L **Quantitative measurement by artificial vision of small bubbles in flowing mercury** [7877-25]
V. C. Paquit, M. W. Wendel, D. K. Felde, B. W. Riemer, Oak Ridge National Lab. (United States)

MACHINE VISION AND INDUSTRIAL APPLICATIONS II

7877 0M **Coded source neutron imaging** [7877-21]
P. Bingham, H. Santos-Villalobos, K. Tobin, Oak Ridge National Lab. (United States)

7877 0N **Towards autonomic computing in machine vision applications: techniques and strategies for in-line 3D reconstruction in harsh industrial environments** [7877-22]
J. Molleda, R. Usamentiaga, D. F. García, F. G. Bulnes, Univ. of Oviedo (Spain)

7877 0O **Evaluating distances using a coded lens camera and a blur metric** [7877-23]
L. J. Angot, C.-C. Chang, Y.-L. Chen, Industrial Technology Research Institute (Taiwan)

7877 0P **Automatic firearm class identification from cartridge cases** [7877-24]
S. Kamalakannan, Texas Tech Univ. (United States); C. J. Mann, P. R. Bingham, T. P. Karnowski, S. S. Gleason, Oak Ridge National Lab. (United States)

INTERACTIVE PAPER SESSION

7877 0U **Segmentation and visualization of anatomical structures from volumetric medical images** [7877-31]
J. Park, S. Park, Mokpo National Univ. (Korea, Republic of); W. Cho, S. Kim, G. Kim, G. Ahn, M. Lee, J. Lim, Chonnam National Univ. (Korea, Republic of)

7877 0V **Extraction and fusion of spectral parameters for face recognition** [7877-32]
B. Boisier, B. Billiot, Z. Abdessalem, P. Gouton, Univ. de Bourgogne (France); J. Y. Hardeberg, Gjøvik Univ. College (France)

7877 0W **Monitoring plant growth using high resolution micro-CT images** [7877-33]
V. C. Paquit, S. S. Gleason, U. C. Kalluri, Oak Ridge National Lab. (United States)

7877 0X **Automating the estimation of coating thickness measurements in the ball crater technique** [7877-35]
J. G. Huang, City Univ. London (United Kingdom) and Teer Coatings Ltd. (United Kingdom); P. Liatsis, City Univ. London (United Kingdom); K. Cooke, D. Teer, Teer Coatings Ltd. (United Kingdom)

Author Index

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2 Image and Signal Processing II
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3 Outdoor Vision
Bushra Jalil, Université de Bourgogne (France)

4 Features and Pattern Recognition
Saleh Mosaddegh, Université de Bourgogne (France)

5 Medical Imaging
Bushra Jalil, Université de Bourgogne (France)

6 Machine Vision and Industrial Applications I
Philip R. Bingham, Oak Ridge National Laboratory (United States)

7 Machine Vision and Industrial Applications II
Saleh Mosaddegh, Université de Bourgogne (France)